Product data sheet

1. General description

Planar passivated very sensitive gate Silicon Controlled Rectifier in a TO92 plastic package.

2. Features and benefits

- Planar passivated for voltage ruggedness and reliability
- · Very sensitive gate

3. Applications

- Ignition circuits
- Low power latching circuits
- Protection / shut-down circuits: lighting ballasts
- Protection / shut-down circuits: Switched Mode Power Supplies

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Absolute	maximum rating					
V_{RRM}	repetitive peak reverse voltage		-	-	400	V
I _{T(AV)}	average on-state half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 1</u> current		-	-	0.5	А
I _{T(RMS)}	RMS on-state current half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 2</u> ; <u>Fig. 3</u>		-	-	0.8	А
	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5	-	-	8	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$	-	-	9	Α
T _j	junction temperature		-	-	125	°C
Static cha	aracteristics				'	
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 \text{ °C}; Fig. 7$	-	-	50	μA
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 268 V; T_j = 125 °C; R_{GK} = 1 kΩ; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 12	500	800	-	V/µs
		V_{DM} = 268 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	-	25	-	V/µs

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5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	Α	anode		. 51
2	G	gate	<u> </u>	А
3	К	cathode	(1) (1) (1) (1) (1) (1) (1) (1) (1) (1)	G sym037

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BT169D-L	TO92	BT169D-L,116	Reel	2000	SOT54 wide pitch	14-Nov-2013

7. Marking

Table 4. Marking codes

Type number	Marking codes
BT169D-L	BT169DL

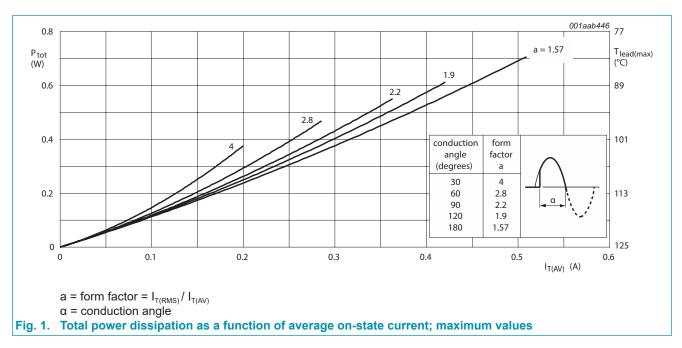
8. Limiting values

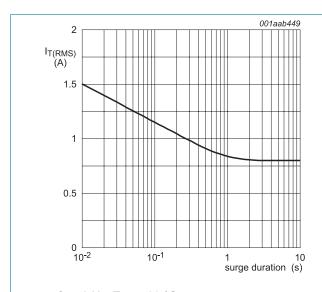
Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage			-	400	V
V_{RRM}	repetitive peak reverse voltage			-	400	V
I _{T(AV)}	average on-state current	half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 1</u>		-	0.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 2</u> ; <u>Fig. 3</u>		-	0.8	А
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 10 ms; Fig. 4; Fig. 5		-	8	A
		half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms		-	9	Α
I ² t	I ² t for fusing	t _p = 10 ms; SIN		-	0.32	A ² s
dl _⊤ /dt	rate of rise of on-state current	$I_T = 2 \text{ A}; I_G = 10 \text{ mA}; dI_G/dt = 100 \text{ mA/}\mu\text{s}$		-	50	A/µs
I _{GM}	peak gate current			-	1	Α
V_{RGM}	peak reverse gate voltage			-	5	V
P_{GM}	peak gate power			-	2	W
$P_{G(AV)}$	average gate power	over any 20 ms period		-	0.1	W
T _{stg}	storage temperature			-40	150	°C
T _j	junction temperature		[1]	-	125	°C

[1] Operation above 110 $^{\circ}\text{C}$ may require the use of a gate to cathode resistor of $1k\Omega$ or less.





f = 50 Hz; T_{lead} = 83 °C

Fig. 2. RMS on-state current as a function of surge duration for sinusoidal currents

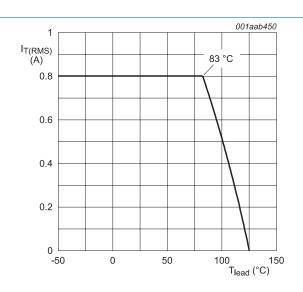
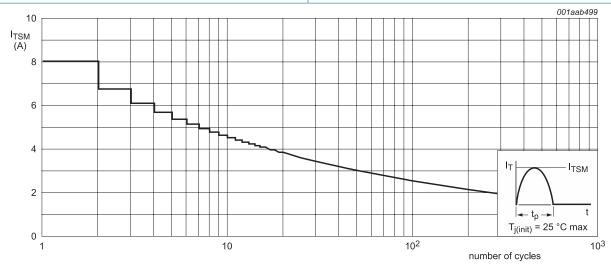


Fig. 3. RMS on-state current as a function of lead temperature; maximum values

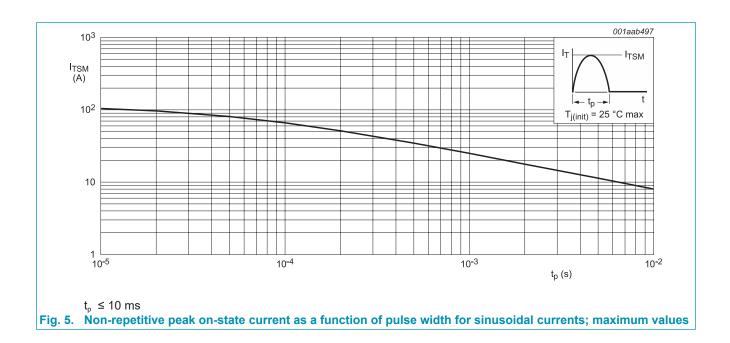


f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal currents cycles; maximum values

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9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-lead)}}$	thermal resistance from junction to lead	Fig. 6	-	-	60	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient free air	printed circuit board mounted: lead length = 4 mm	-	150	-	K/W

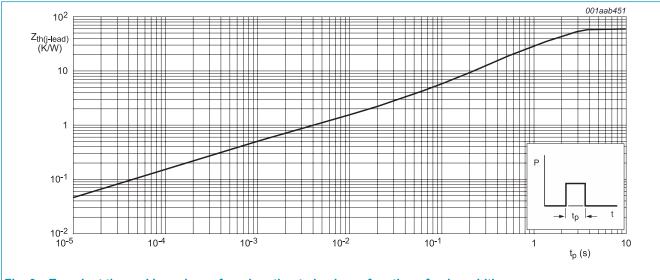


Fig. 6. Transient thermal impedance from junction to lead as a function of pulse width

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics		,			
I _{GT}	gate trigger current $V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 ^{\circ}\text{C};$ Fig. 7		-	-	50	μA
IL	latching current	$V_D = 12 \text{ V}; I_G = 0.5 \text{ mA}; T_j = 25 ^{\circ}\text{C};$ Fig. 8	-	2	4	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	0.4	1	mA
V _T	on-state voltage	I _T = 1.2 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.25	1.7	V
V_{GT}	gate trigger voltage	V _D = 12 V; I _T = 10 mA; T _j = 25 °C; Fig. 11	-	0.5	0.8	V
		V _D = 12 V; I _T = 10 mA; T _j = 125 °C	0.2	0.3	-	V
I _D of	off-state current	$V_D = 400 \text{ V}; R_{GK} = 1 \text{ k}\Omega; T_j = 25 \text{ °C}$	-	-	2	μA
		$V_D = 400 \text{ V}; R_{GK} = 1 \text{ k}\Omega; T_j = 125 \text{ °C}$	-	0.05	0.1	mA
I _R	reverse current	$V_R = 400 \text{ V}; T_j = 25 \text{ °C}; R_{GK} = 1 \text{ k}\Omega$	-	0.05	2	μA
		$V_R = 400 \text{ V}; T_j = 125 \text{ °C}; R_{GK} = 1 \text{ k}\Omega$	-	0.05	0.1	mA
Dynamic	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 268 V; T_j = 125 °C; R_{GK} = 1 k Ω ; (V_{DM} = 67% of V_{DRM}); exponential waveform; Fig. 12	500	800	-	V/µs
		V_{DM} = 268 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 12	-	25	-	V/µs

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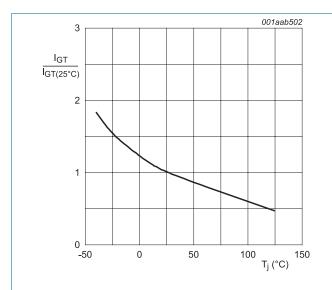
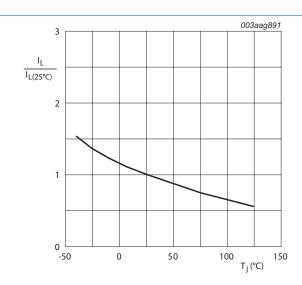
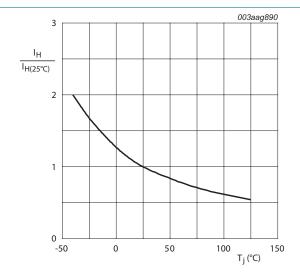


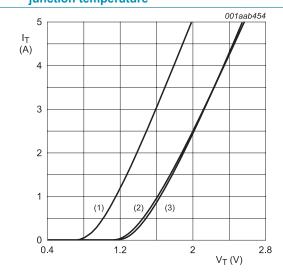
Fig. 7. Normalized gate trigger current as a function of junction temperature



 R_{GK} = 1 k Ω Fig. 8. Normalized latching current as a function of junction temperature



 $R_{\text{GK}} = 1 \; k\Omega$ Fig. 9. Normalized holding current as a function of junction temperature



 V_o = 1.067 V; R_s = 0.187 Ω (1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values (3) T_i = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

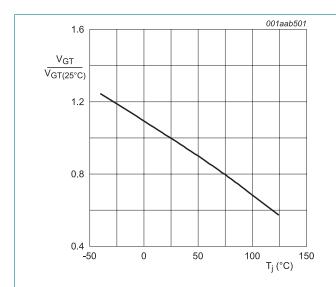
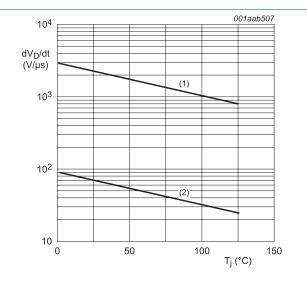
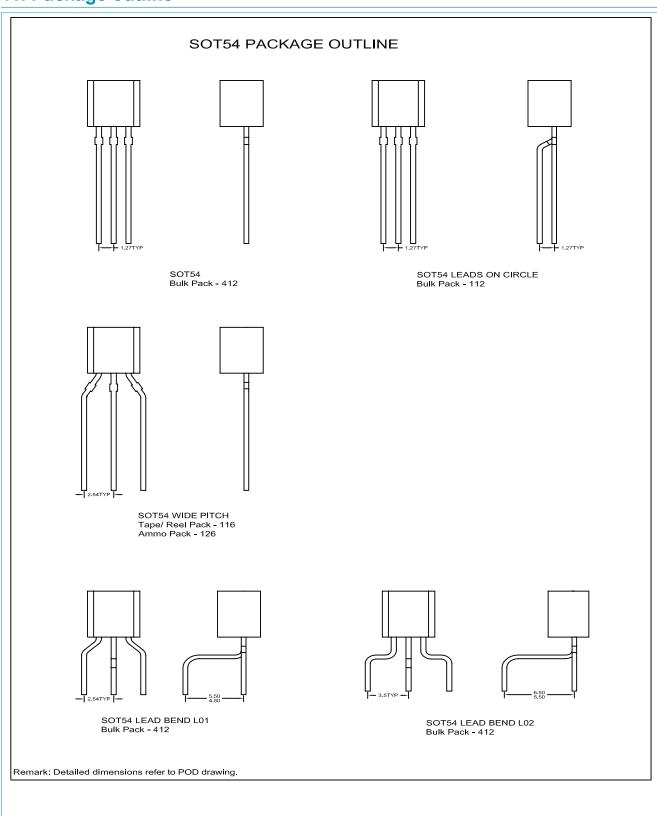


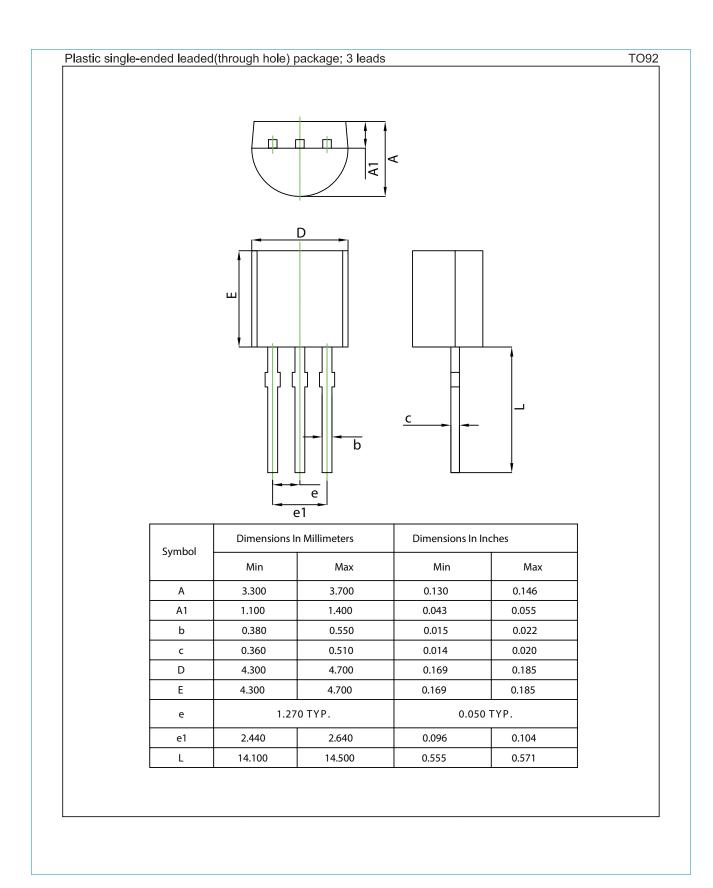
Fig. 11. Normalized gate trigger voltage as a function of junction temperature



(1) R_{GK} = 1 kΩ;
(2) gate open circuit
Fig. 12. Critical rate of rise of off-state voltage as a function of junction temperature; typical values

11. Package outline





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12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Date of release: 12 October 2021

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